 	Note:	_

Application/Control No.	Applicant(s)/Patent un Reexamination	der
10/085,063	ARAI ET AL.	
Examiner	Art Unit	_
Binh X. Tran	1765	

				
	SEARCHED			
Class	Subclass	Date	Examiner	
438	691	6/30/2005	タナ	
438	692	6/30/2005	断	
438	693	6/30/2005	BT	
438	697	6/30/2005	BT	
438	699	6/30/2005	135	
		_		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
438	691	6/30/2005	br
438	692	6/30/2005	BT
438	693	6/30/2005	BY
438/697 438/699		6/30/2005	BT

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Update search using USPAT, US- PGPUB, EPO, JPO, DERWENT database	6/30/2005	BY
·		
•		